

1. General description

Planar passivated SCR with sensitive gate in a TO252 (DPAK) surface mountable plastic package. These devices are intended to be interfaced directly to microcontrollers, logic integrated circuits and other low power gate trigger circuits.

2. Features and benefits

- Sensitive gate
- · Planar passivated for voltage ruggedness and reliability
- Direct triggering from low power drivers and logic ICs
- Surface mountable package

3. Applications

- General purpose switching
- Protection Circuits

4. Quick reference data

reference data						
Parameter	Conditions		Min	Тур	Max	Unit
repetitive peak off- state voltage		[1]	-	-	600	V
repetitive peak reverse voltage			-	-	600	V
average on-state current	half sine wave; T _{mb} ≤ 111 °C; <u>Fig. 1</u>		-	-	2.5	A
RMS on-state current	half sine wave; T _{mb} ≤ 111 °C; <u>Fig. 2;</u> <u>Fig. 3</u>		-	-	4	A
non-repetitive peak on- state current	half sine wave; T _{j(init)} = 25 °C; t _p = 10 ms; <u>Fig. 4; Fig. 5</u>		-	-	35	A
	half sine wave; T _{j(init)} = 25 °C; t _p = 8.3 ms		-	-	38	A
junction temperature		[2]	-	-	125	°C
eristics						
gate trigger current	V _D = 12 V; I _T = 0.1 A; T _j = 25 °C; <u>Fig. 7</u>		-	15	200	μA
acteristics						,
rate of rise of off-state voltage	V_{DM} = 402 V; T _j = 125 °C; R _{GK} = 100 Ω; (V_{DM} = 67% of V_{DRM}); exponential waveform; Fig. 12		-	50	-	V/µs
	Parameter repetitive peak off- state voltage repetitive peak reverse voltage average on-state current RMS on-state current non-repetitive peak on- state current junction temperature eristics gate trigger current acteristics rate of rise of off-state	ParameterConditionsrepetitive peak off- state voltagerepetitive peak reverse voltageaverage on-state currenthalf sine wave; $T_{mb} \le 111 ^{\circ}C$; Fig. 1RMS on-state currenthalf sine wave; $T_{mb} \le 111 ^{\circ}C$; Fig. 2; Fig. 3non-repetitive peak on- state currenthalf sine wave; $T_{j(init)} = 25 ^{\circ}C$; $t_p = 10 ^{o}ms; Fig. 4; Fig. 5non-repetitive peak on-state currenthalf sine wave; T_{j(init)} = 25 ^{\circ}C;t_p = 8.3 ^{o}msjunction temperaturegate trigger currentV_D = 12 ^{o}V; ^{I}T = 0.1 ^{A}; ^{T}T_{j} = 25 ^{\circ}C; ^{Fig. 7}acteristicsrate of rise of off-statevoltageV_{DM} = 402 ^{o}V; ^{T}T_{j} = 125 ^{\circ}C; ^{R}GK = 100 ^{o}C; (V_{DM} = 67\% of V_{DRM}); exponential$	ParameterConditionsrepetitive peak off- state voltage[1]repetitive peak reverse voltage[1]average on-state currenthalf sine wave; $T_{mb} \le 111 ^{\circ}C$; Fig. 1RMS on-state currenthalf sine wave; $T_{mb} \le 111 ^{\circ}C$; Fig. 2; 	ParameterConditionsMinrepetitive peak off- state voltage[1]-repetitive peak reverse voltage[1]-average on-state currenthalf sine wave; $T_{mb} \le 111 ^{\circ}C$; Fig. 1-RMS on-state currenthalf sine wave; $T_{mb} \le 111 ^{\circ}C$; Fig. 2; Fig. 3-non-repetitive peak on- state currenthalf sine wave; $T_{j(init)} = 25 ^{\circ}C$; $t_p = 10 ms; Fig. 4; Fig. 5-non-repetitive peak on-state currenthalf sine wave; T_{j(init)} = 25 ^{\circ}C;t_p = 8.3 ms-junction temperature[2]-gate trigger currentV_D = 12 ^{\circ}V; I_T = 0.1 ^{\circ}A; T_j = 25 ^{\circ}C; Fig. 7-rate of rise of off-statevoltageV_{DM} = 402 ^{\circ}V; T_j = 125 ^{\circ}C; R_{GK} = 100 ^{\circ}\Omega;(V_{DM} = 67\% of V_{DRM}); exponential-$	ParameterConditionsMinTyprepetitive peak off- state voltage[1]repetitive peak reverse voltageaverage on-state currenthalf sine wave; $T_{mb} \le 111 ^{\circ}C$; Fig. 1RMS on-state current state currenthalf sine wave; $T_{mb} \le 111 ^{\circ}C$; Fig. 2; Fig. 3non-repetitive peak on- state currenthalf sine wave; $T_{j(init)} = 25 ^{\circ}C$; $t_p = 10 ^{ons}$; Fig. 4; Fig. 5half sine wave; $T_{j(init)} = 25 ^{\circ}C$; $t_p = 8.3 ^{ons}$ junction temperature[2]gate trigger current $V_D = 12 ^{\circ}V$; $I_T = 0.1 ^{ons}$; $Fig. 7$ -15acteristicsrate of rise of off-state $(V_{DM} = 67\% ^{ons} O ^{ons})$; exponential-50	ParameterConditionsMinTypMaxrepetitive peak off- state voltage[1]600repetitive peak reverse voltage600average on-state currenthalf sine wave; $T_{mb} \le 111 ^{\circ}C$; Fig. 1600average on-state currenthalf sine wave; $T_{mb} \le 111 ^{\circ}C$; Fig. 2; Fig. 32.5RMS on-state current state currenthalf sine wave; $T_{mb} \le 111 ^{\circ}C$; Fig. 2; Fig. 34non-repetitive peak on- state currenthalf sine wave; $T_{j(init)} = 25 ^{\circ}C$; $t_p = 10 ms; Fig. 4; Fig. 535half sine wave; T_{j(init)} = 25 ^{\circ}C;t_p = 8.3 ms125junction temperature[2]125gate trigger currentV_D = 12 V; I_T = 0.1 A; T_j = 25 ^{\circ}C; Fig. 7-15200acteristicsrate of rise of off-statevoltageV_{DM} = 402 V; T_j = 125 ^{\circ}C; R_{GK} = 100 \Omega;(V_{DM} = 67\% of V_{DRM}); exponential-50-$

- Although not recommended, off-state voltages up to 800V may be applied without damage, but the thyristor may switch to the on-state. The rate of rise of current should not exceed 15 A/µs.
- [2] Operation above 110° C may require the use of a gate to cathode resistor of $1k\Omega$ or less.

5. Pinning information

Table 2. F	Pinning inf	ormation		
Pin	Symbol	Description	Simplified outline	Graphic symbol
1	К	cathode	mb	А- ДТ К
2	А	anode[1]		G sym037
3	G	gate		Symosi
mb	A	mounting base; connected to anode	L C C C C C C C C C C C C C C C C C C C	

[1] It is not possible to connect to pin 2 of the SOT428 package.

6. Ordering information

Table 3. Ordering information

Type number	Package					
	Name	Description	Version			
BT150S-600R	DPAK	plastic single-ended surface-mounted package (DPAK); 3 leads (one lead cropped)	TO252N			

7. Marking

Table 4. Marking codes				
Type number	Marking code			
BT150S-600R	150S6			

8. Limiting values

Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions		Min	Max	Unit
V _{DRM}	repetitive peak off-state voltage		[1]	-	600	V
V _{RRM}	repetitive peak reverse voltage			-	600	V
I _{T(AV)}	average on-state current	half sine wave; T _{mb} ≤ 111 °C; <u>Fig. 1</u>		-	2.5	А
I _{T(RMS)}	RMS on-state current	half sine wave; T _{mb} ≤ 111 °C; <u>Fig. 2;</u> <u>Fig. 3</u>		-	4	A
I _{TSM}	non-repetitive peak on- state current	half sine wave; T _{j(init)} = 25 °C; t _p = 10 ms; Fig. 4; Fig. 5		-	35	A
		half sine wave; T _{j(init)} = 25 °C; t _p = 8.3 ms		-	38	А
l ² t	I ² t for fusing	t _p = 10 ms; SIN		-	6.1	A²s
dl _T /dt	rate of rise of on-state current	I _G = 50 mA		-	50	A/µs
I _{GM}	peak gate current			-	2	А
V _{RGM}	peak reverse gate voltage			-	5	V
P _{GM}	peak gate power			-	5	W
P _{G(AV)}	average gate power	over any 20 ms period		-	0.5	W
T _{stg}	storage temperature			-40	150	°C
T _j	junction temperature		[2]	-	125	°C

[1] Although not recommended, off-state voltages up to 800V may be applied without damage, but the thyristor may switch to the on-state. The rate of rise of current should not exceed 15 A/ μ s. Operation above 110°C may require the use of a gate to cathode resistor of 1k Ω or less.

[2]

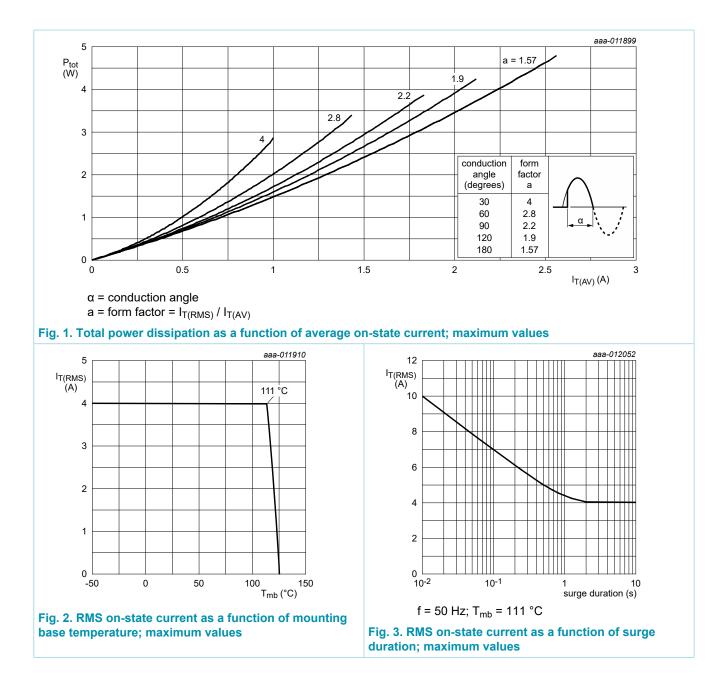
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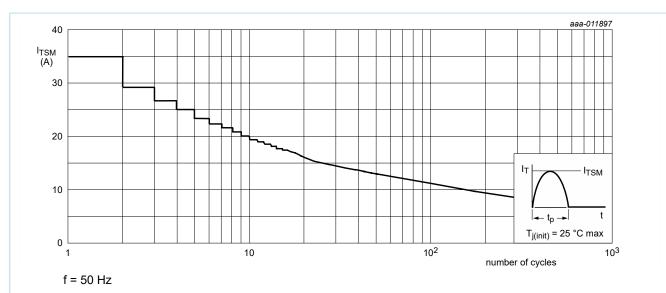


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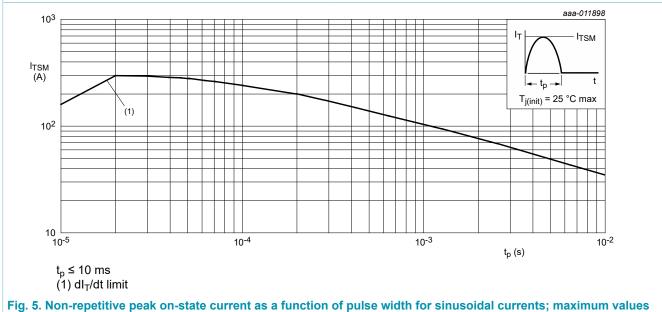
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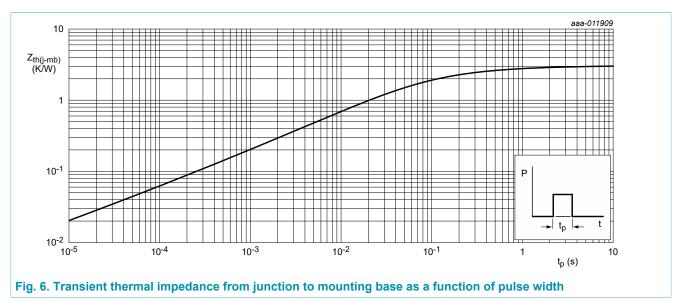






9. Thermal characteristics

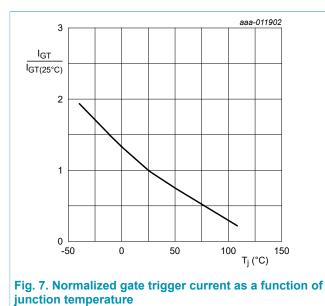
Table 6. The	rmal characteristics					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
R _{th(j-mb)}	thermal resistance from junction to mounting base	<u>Fig. 6</u>	-	-	3	K/W
R _{th(j-a)}	thermal resistance from junction to ambient free air	Device mounted on an FR4 Printed- Circuit Board (PCB), single-sided copper, tin-plated and standard footprint	-	75	-	K/W

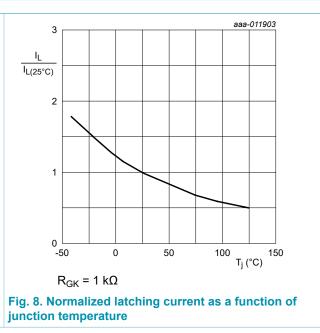


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10. Characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static chara	acteristics	· · · · ·				
I _{GT}	gate trigger current	V _D = 12 V; I _T = 0.1 A; T _j = 25 °C; <u>Fig. 7</u>	-	15	200	μA
IL	latching current	V_D = 12 V; I _G = 0.1 A; T _j = 25 °C; <u>Fig. 8</u>	-	0.17	10	mA
I _H	holding current	V _D = 12 V; T _j = 25 °C; <u>Fig. 9</u>	-	0.1	6	mA
V _T	on-state voltage	I _T = 5 A; T _j = 25 °C; <u>Fig. 10</u>	-	1.23	1.8	V
V _{GT}	gate trigger voltage	V _D = 12 V; I _T = 0.1 A; T _j = 25 °C; Fig. 11	-	0.4	1	V
		V_D = 600 V; I _T = 0.1 A; T _j = 110 °C; Fig. 11	0.1	0.2	-	V
I _D	off-state current	V _D = 600 V; T _j = 125 °C	-	0.1	0.5	mA
I _R	reverse current	V _R = 600 V; T _j = 125 °C	-	0.1	0.5	mA
Dynamic ch	naracteristics		·			
dV _D /dt	rate of rise of off-state voltage	V_{DM} = 402 V; T _j = 125 °C; R _{GK} = 100 Ω; (V _{DM} = 67% of V _{DRM}); exponential waveform; Fig. 12	-	50	-	V/µs
t _{gt}	gate-controlled turn-on time	I_{TM} = 10 A; V _D = 600 V; I _G = 5 mA; dI _G / dt = 0.2 A/µs; T _j = 25 °C	-	2	-	μs
t _q	commutated turn-off time	$V_{DM} = 402 \text{ V}; \text{ T}_{j} = 125 \text{ °C}; \text{ I}_{TM} = 8 \text{ A};$ $V_{R} = 10 \text{ V}; (dI_{T}/dt)_{M} = 10 \text{ A}/\mu\text{s}; dV_{D}/$ $dt = 2 \text{ V}/\mu\text{s}; \text{ R}_{GK(ext)} = 1 \text{ k}\Omega; (V_{DM} = 67\% \text{ of } V_{DRM})$	-	100	-	μs

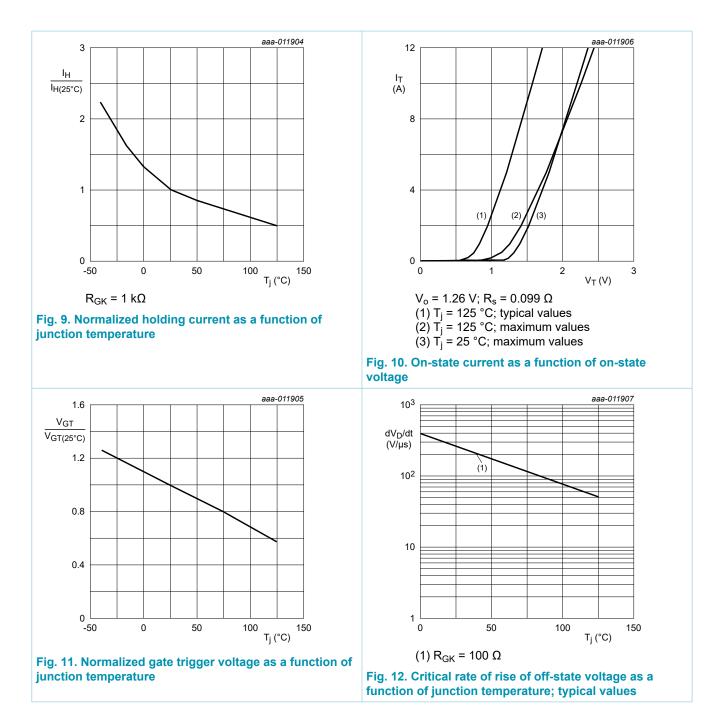




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11. Package outline

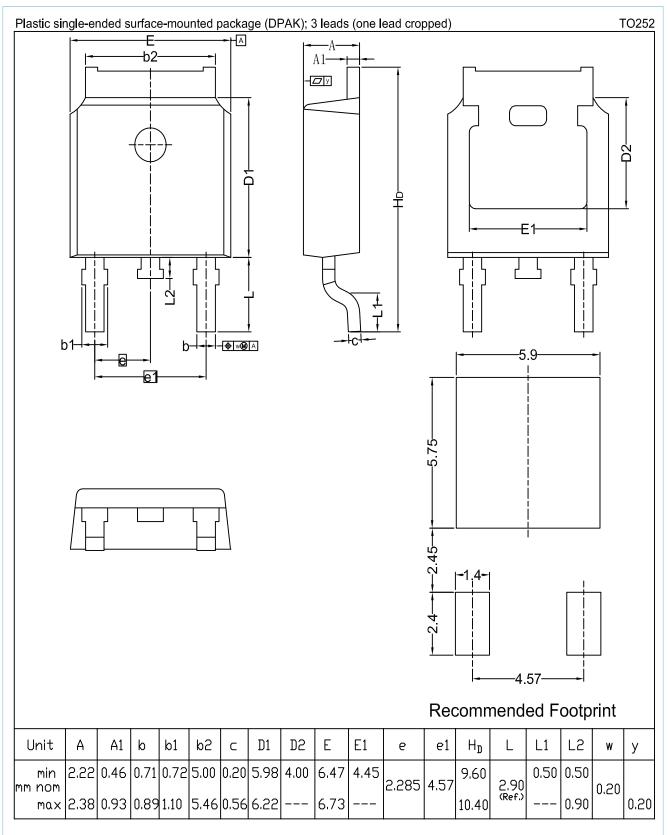


Fig. 13. Package outline DPAK (TO252N)

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12. Legal information

Data sheet status

Document status [1][2]	Product status [<u>3]</u>	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

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